

# RELIABILITY DATA

## LT927 / LT928 / LT1166 / LT1794 / LT6300 / LT6301

8/21/2006

### • OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(1)</sup> AT +125°C	NUMBER OF <sup>(2)</sup> FAILURES
PLASTIC DIP	80	9526	9526	80.00	0
SSOP/TSSOP	127	0040	0047	90.44	0
	207			170.44	0

### • HIGHLY ACCELERATED STRESS TEST AT +131°C/85%RH

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(4)</sup> AT +85°C	NUMBER OF FAILURES
SSOP/TSSOP	10	0127	0127	10.00	0
	10			10.00	0

### • PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
PLASTIC DIP	50	0122	0122	1.20	0
SOIC/SOT/MSOP	150	0113	0129	51.60	0
SSOP/TSSOP	1,108	0045	0534	136.63	0
	1,308			189.43	0

### • TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	150	0113	0129	153.30	0
SSOP/TSSOP	1,084	0045	0534	326.74	0
	1,234			480.04	0

### • THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SSOP/TSSOP	1,114	0045	0534	324.20	0
	1,114			324.20	0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 10.79 FITS

(3) Mean Time Between Failures in Years = 10,572

(4) Assumes 20X Acceleration from 85°C to +131°C

Note: 1 FIT = 1 Failure in One Billion Hours.